



7th IEEE International Workshop on Silicon Debug and Diagnosis – SDD 2011

Thursday Sept 22nd – Friday Sept 23rd
Anaheim, California

Immediately following the 2011 International Test Conference

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Program Chair:

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Scope and Mission

Troubleshooting how and why systems and circuits fail is important and is rapidly growing in industry significance. Debug and diagnosis may be needed for yield improvement, process monitoring, correcting the design function, failure mode learning for R&D, or just getting a working first prototype. This detective work is however very tricky. Sources of difficulty include circuit and system complexity, packaging, limited physical access, shortened product creation cycle and time-to-market. New and efficient solutions for debug and diagnosis have a much needed and highly visible impact on productivity.

SDD 2011 will be held in Anaheim, California, USA. It is the seventh of a series of highly successful technical workshops that consider issues related to debug & diagnosis of semiconductor circuits and systems - from prototype bring-up to volume production.

The topics of interest include, but are not limited to, the following:

Debug Techniques and Methodologies	Microprocessor, FPGA, IP, SOC Debug
Design for Debug	Infrastructure IP for SDD
DFT Reuse for Debug and Diagnosis	System Level Debug & Diagnosis
Manufacturing & Prototype Environment	Emulation & Hardware Accelerator
Debug Standardization	Cross-geography turn-on, debug & diagnosis issues
Case Studies	SDD vs. Yield & TTM

Author Information

The workshop objective is to facilitate an interactive information exchange. Extended abstracts and papers may be short. Proposals that describe open issues, industry/technology needs or opinions are valuable to the program.

Length Guideline: ranging from one page extended abstract to 8 pages

Submissions due: **August 1st, 2011**

Acceptance Notification: **August 20th, 2011**

Final versions: **September 3rd, 2011**

Proposals for discussion panels, new topics and other special sessions are also invited. Much of the success of the event has been a result of crafting sessions based on participant interest. Please submit a 1 page abstract or discuss the issue with Program or Special Sessions Chairs

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SDD11 is sponsored by the IEEE Computer Society Test Technology Technical Council.
For more information on SDD11, visit the website at: <http://www.sdd-online.org>

**Preliminary Call
for
Participation**

